

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 2813/USA/SILICON/MBE

SERIAL NO.:  
09/096,728**LIST OF ART CITED BY APPLICANT**

(Use several sheets if necessary)

APPLICANT: GRIMBERGEN, ET AL.

FILING DATE: JUNE 11, 1998

GROUP: 1763

**U.S. PATENT DOCUMENTS**

Examiner Initial		DOCKET NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JK</i>	AA	3	1	7	0	3	8	3	02/1965	HUNT	454	370	
<i>JK</i>	AB	3	3	1	6	4	6	8	04/1967	HANKS	361	233	
<i>JK</i>	AC	4	0	3	7	9	4	5	07/1977	WOLLAM	350	319	
<i>JK</i>	AD	5	0	7	4	9	8	5	12/1991	TAMURA, ET AL.	204	298.11	
<i>JK</i>	AE	5	1	2	9	9	9	4	07/14/92	EBBING, ET AL.	156	643	
<i>JK</i>	AF	5	2	7	7	7	4	6	01/1994	ANDERSON	156	603	
<i>JK</i>	AG	5	2	9	0	3	8	3	03/01/94	KOSHIMIZU	156	345	
<i>JK</i>	AH	5	6	2	2	6	3	5	04/22/97	CUOMO, ET AL.	216	68	
<i>JK</i>	AI	5	7	3	8	7	5	6	04/14/98	LIU	156	627.1	
<i>JK</i>	AJ	5	8	0	0	6	8	8	09/01/98	LANTSMAN, ET AL.	204	298.11	
<i>JK</i>	AK	6	0	0	6	6	9	4	02/1965	DEORNELLAS, ET AL.	118	723	
	AL												

**FOREIGN PATENT DOCUMENTS**

		DOCKET NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
<i>JK</i>	AL	0	6	0	7	7	9	7	07/27/94	EP APPLICATION				
<i>JK</i>	AM	0	8	0	1	4	1	3	10/15/97	EP APPLICATION				
<i>JK</i>	AN	0	9	0	8	9	2	2	04/14/99	EP APPLICATION				
<i>JK</i>	AO	61	1	6	0	9	2	6	07/21/86	JAPAN ABSTRACT			✓	
<i>JK</i>	AP	03	0	1	5	1	9	8	01/23/91	JAPAN ABSTRACT			✓	
<i>JK</i>	AQ	WO	98	4	4	5	3	5	10/08/98	PCT APPLICATION				
<i>JK</i>	AR	WO	98	4	8	4	4	4	10/29/98	PCT APPLICATION				
	AS	WO	99	1	4	7	9	1	03/25/99	PCT APPLICATION				

**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

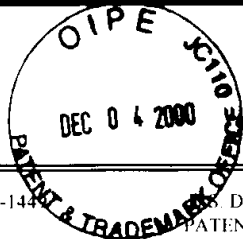
<i>JK</i>	AT	PCT Search Report dated September 15, 1999
	AU	
	AV	

EXAMINER

*JK*

DATE CONSIDERED 11/14/01

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 2813 D1/SILICON

SERIAL NO  
09/610.237**LIST OF ART CITED BY APPLICANT**

(Use several sheets if necessary)

APPLICANT: Grimbergen, et al

FILING DATE: 7/5/2000

GROUP: 1763

**U.S. PATENT DOCUMENTS**

Examiner Initial	DOCKET NUMBER								DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	3	5	1	4	3	9	1	05/05/67	Hablanian, et al	204	298		
AB	4	0	3	3	2	8	7	07/05/77	Alexander, Jr., et al	118	49.1		
AC	5	2	7	7	7	5	1	01/11/94	Ogle	156	643		
AD	5	4	4	5	7	0	9	08/29/95	Kojima, et al	216	71		
AE	5	8	0	0	6	1	9	09/01/98	Holland, et al	118	723I		
AF	5	8	0	4	0	4	6	09/08/98	Sawada, et al	204	298.11		
AG	5	8	1	4	1	5	4	09/29/98	Boitnott	118	723R		
AH	5	8	3	7	0	5	7	11/17/98	Koyama, et al	118	723VE		
AI	5	8	7	4	7	0	4	02/23/99	Gates	219	121.43		
<del>AJ</del>	<del>6</del>	<del>0</del>	<del>0</del>	<del>6</del>	<del>6</del>	<del>0</del>	<del>4</del>	<del>12/28/99</del>	<del>DeOmelias, et al</del>	<del>118</del>	<del>723I</del>		
AK													
AL													
AM													
AN													

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													YES	NO
AO														
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**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

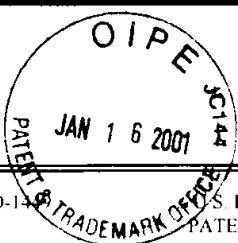
AT	Alan R. Reinberg, <i>Plasma Etch Equipment Technology</i> , M. Triodes, Perkin-Elmer Corporation, Norwalk, Connecticut, (c) 1989 by Academic Press, Inc., ISBN 0-12-469370-9; pp. 350-351
AW	Plasma Etching Technology, 10-11 February, 1997, Burlingame, California, Continuing Education in Engineering, University Extension, U. of California, Berkeley, <i>Plasma Etching Technology An Overview</i> , D.L. Flamm, D.L. Flamm 1992-1996, title 95011501v2, D.L. Flamm 1995, src5012608, 3 pgs.
AX	PCT Notification of Transmittal of the International Search Report or the Declaration for PCT/US98/25437, Int'l Filing Date 01 December 1998, mailed March 19, 1999

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\* See Paper #2

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Examiner Initial		DOCKET NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
hK	AA	5	3	7	0	7	6	5	12/06/94	Dandi	156	643	
hK	AB	5	5	3	1	8	6	2	07/02/96	Otsubo, et al.	156	643.1	
	AC												
	AD												
	AE												
	AF												
	AG												
	AH												
	AI												
	AJ												
	AK												

**FOREIGN PATENT DOCUMENTS**

		DOCKET NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
hK	AL	6	3	2	5	3	6	17	10/1988	Japan	—	—	YES	
	AM													
	AN													
	AO													
	AP													

**OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)**

	AQ	
	AR	
	AS	

EXAMINER

hK

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